

Form PTO-1449 U.S. Department of Commerce  
(REV. 2-82) Patent and Trademark Office

Atty. Docket No.  
36179/US/2-475387-30

Serial No.  
10/577,562

# INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(Use several sheets if necessary)

Applicant(s)  
Seok-Hyun Yun et al.

Filing Date  
April 27, 2006

Confirmation No.  
3634

## U.S. PATENT DOCUMENTS

*Exam. Init.	Document No.							Date	Name	Class	Subclass	Filing Date if Appropriate
	4	5	3	3	2	4	7	August 6, 1985	Epworth e e e e e e e e			
	6	7	4	1	3	5	5	May 25, 2004	Drabarek e e e e e e e e			
2005	0	0	7	5	5	4	7	April 7, 2005	Wang e e e e e e e e			
2005	0	0	8	3	5	3	4	April 21, 2005	Riza et al. e e e e e e e e			
	3	9	7	3	2	1	9	August 3, 1976	Tang et al.			
	3	9	8	3	5	0	7	September 28, 1976	Tang et al.			
2006	0	1	0	3	8	5	0	May 18, 2006	Alphonse et al. e e e e e e e e			
	4	8	9	2	4	0	6	January 9, 1990	Waters e e e e e e e e			
	5	7	1	6	3	2	4	February 10, 1998	Toida φ			
	6	4	5	9	4	8	7	October 1, 2002	Chen et al. φ			
2002	0	0	9	3	6	6	2	July 18, 2002	Chen et al. φ			
	6	3	5	9	6	9	2	March 19, 2002	Groot φ φ φ			
	6	9	0	3	8	2	0	June 7, 2005	Wang φ φ φ φ			
2006	0	2	4	4	9	7	3	November 2, 2006	Yun et al. φ φ φ φ φ φ			
	5	2	2	8	0	0	1	July 13, 1993	Birge et al. φ φ φ φ φ φ			
	6	6	8	7	0	3	6	February 3, 2004	Riza φ φ φ φ φ φ			
	4	4	2	8	6	4	3	January 31, 1984	Kay φ φ φ φ φ φ			
	4	9	6	5	5	9	9	October 23, 1990	Roddy et al. φ φ φ φ φ φ			

Examiner

Date Considered

\* Examiner: Initial citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO-1449 U.S. Department of Commerce  
(REV. 2-82) Patent and Trademark Office

Atty. Docket No.  
36179/US/2-475387-30

Serial No.  
10/577,562

**INFORMATION DISCLOSURE STATEMENT  
BY APPLICANT**

(Use several sheets if necessary)

Applicant(s)  
Seok-Hyun Yun et al.

Filing Date  
April 27, 2006

Confirmation No.  
3634

		4	3	0	3	3	0	0	December 1, 1981	Pressiat et al.			
		6	8	3	9	4	9	6	January 4, 2005	Mills et al.			
2004	0	1	3	3	1	9	1		July 8, 2004	Momiuchi et al. φφφφφφφφ			
		5	8	4	0	0	7	5	November 24, 1998	Mueller et al. φφφφφφφφ			
2003	0	2	1	6	7	1	9		November 20, 2003	Debenedictis et al. φφφφφφφφ			
2006	0	1	5	5	1	9	3		July 13, 2006	Leonardi et al. φφφφφφφφ			
2003	0	1	9	9	7	6	9		October 23, 2003	Podoleanu et al. φφφφφφφφφφ			
2004	0	2	1	2	8	0	8		October 28, 2004	Okawa et al. φφφφφφφφφφ			

**FOREIGN PATENT DOCUMENT**

Document No.									Date	Country	Class	SubClass	Translator Yes No	
	9	6	2	8	2	1	2		September 19, 1996	WIPO φφφφφφφφφφ φ				
	0	9	3	3	0	9	6		August 4, 1999	European φφφφφφφφφφ φ				
	4	1	0	5	2	2	1		September 12, 1991	Germany				
	0	1	0	8	5	7	9		February 8, 2001	WIPO φφφφφφφφ				
	9	9	0	5	4	8	7		February 4, 1999	WIPO φφφφφφφφ				
200	5	0	8	2	2	2	5		September 9, 2005	WIPO φφφφφφφφφφ				
200	4	0	3	4	8	6	9		April 29, 2004	WIPO φφφφφφφφφφ				

Examiner

Date Considered

\* Examiner: Initial citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO-1449 U.S. Department of Commerce  
(REV. 2-82) Patent and Trademark Office

Atty. Docket No.  
36179/US/2-475387-30

Serial No.  
10/577,562

**INFORMATION DISCLOSURE STATEMENT  
BY APPLICANT**

(Use several sheets if necessary)

Applicant(s)  
Seok-Hyun Yun et al.

Filing Date  
April 27, 2006

Confirmation No.  
3634

	0	3	0	5	2	4	7	8	June 26, 2003	WIPO φφφφφφφφφφ				
	200	7	0	3	8	7	8	7	April 5, 2007	WIPO φφφφφφφφφφ				

References cited in Office Action dated November 15, 2007 for U.S. Patent Application No. 11/285,301  
 References cited in European Patent Office Search Report for Application No. 05791226.3  
 References cited in Office Action dated December 18, 2007 for U.S. Patent Application No. 11/288,994  
 References cited in Office Action dated December 21, 2007 for U.S. Patent Application No. 11/264,655  
 Reference cited in Office Action dated January 3, 2008 for U.S. Patent Application No. 10/997,789  
 Reference cited in Office Action dated January 10, 2008 for U.S. Patent Application No. 11/435,228  
 Reference cited in Office Action dated January 10, 2008 for U.S. Patent Application No. 11/410,937  
 Reference cited in Office Action dated January 11, 2008 for U.S. Patent Application No. 11/445,990  
 Reference cited in Office Action dated February 4, 2008 for U.S. Patent Application No. 10/861,179  
 References cited in International Search Report PCT/US2007/061481 dated March 17, 2008  
 References cited in International Search Report PCT/US2007/078254 dated March 28, 2008  
 References cited in International Search Report for Application No. PCT/US2007/068233 dated February 21, 2008  
 References cited in International Search Report for Application No. PCT/US2007/060787 dated March 18, 2008  
 References cited in International Search Report and Written Opinion for Application No. PCT/US2007/061463 dated January 23, 2008

**OTHER DOCUMENTS (including Author, Title Date, Pertinent Pages, Etc.)**

			Tang C. L. et al., "Wide-band electro-optical tuning of semiconductor lasers", Applied Physics Letters, Vol. 30, No. 2, January 15, 1977, pages 113-116
			Tang C. L. et al., "Transient effects in wavelength-modulated dye lasers", Applied Physics Letters, Vol. 26, No. 9, May 1, 1975, pages 534-537
			Telle M. John, et al., "Very rapid tuning of cw dye laser", Applied Physics Letters, Vol. 26, No. 10, May 15, 1975, pages 572-574
			Telle M. John, et al., "New method for electro-optical tuning of tunable lasers", Applied Physics Letters, Vol. 24, No. 2, January 15, 1974, pages 85-87

Examiner

Date Considered

\* Examiner: Initial citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO-1449 U.S. Department of Commerce  
(REV. 2-82) Patent and Trademark Office

Atty. Docket No.  
36179/US/2-475387-30

Serial No.  
10/577,562

**INFORMATION DISCLOSURE STATEMENT  
BY APPLICANT**

(Use several sheets if necessary)

Applicant(s)  
Seok-Hyun Yun et al.

Filing Date  
April 27, 2006

Confirmation No.  
3634

Schmitt M. Joseph et al. "OCT elastography: imaging microscopic deformation and strain of tissue", Optics Express, Vol. 3, No. 6, September 14, 1998, pages 199-211 eeeeeeeee

M. Gualini Muddassir et al., "Recent Advancements of Optical Interferometry Applied to Medicine", IEEE Transactions on Medical Imaging, Vol. 23, No. 2, February 2004, pages 205-212  
Maurice L. Roch et al. "Noninvasive Vascular Elastography: Theoretical Framework", IEEE Transactions on Medical Imaging, Vol. 23, No. 2, February 2004, pages 164-180 eeeeeeeee

Kirkpatrick J. Sean et al. "Optical Assessment of Tissue Mechanical Properties", Proceedings of the SPIE - The International Society for Optical Engineering SPIE - Vol. 4001, 2000, pages 92-101 eeeeeeeee

Lisaukas B. Jennifer et al., "Investigation of Plaque Biomechanics from Intravascular Ultrasound Images using Finite Element Modeling", Proceedings of the 19<sup>th</sup> International Conference - IEEE October 30 - November 2, 1997, pages 887-888 eeeeeeeee

Parker K. J. et al., "Techniques for Elastic Imaging: A Review", IEEE Engineering in Medicine and Biology, November/December 1996, pages 52-59 eeeeeeeee

Copy of European Patent Office Search Report for Application No. 05791226.3

Dubois Arnaud et al., "Ultrahigh-resolution OCT using white-light interference microscopy", Proceedings of SPIE, 2003, Vol. 4956, pages 14-21 φφ

Copy of Office Action dated January 3, 2008 for U.S. Patent Application No. 10/997,789

Copy of Office Action dated December 21, 2007 for U.S. Patent Application No. 11/264,655

Copy of Office Action dated December 18, 2007 for U.S. Patent Application No. 11/288,994

Copy of Office Action dated January 10, 2008 for U.S. Patent Application No. 11/435,228

Copy of Office Action dated January 10, 2008 for U.S. Patent Application No. 11/410,937

Copy of Office Action dated January 11, 2008 for U.S. Patent Application No. 11/445,990

Examiner

Date Considered

\* Examiner: Initial citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO-1449 U.S. Department of Commerce  
(REV. 2-82) Patent and Trademark Office

Atty. Docket No.  
36179/US/2-475387-30

Serial No.  
10/577,562

**INFORMATION DISCLOSURE STATEMENT  
BY APPLICANT**

(Use several sheets if necessary)

Applicant(s)  
Seok-Hyun Yun et al.

Filing Date  
April 27, 2006

Confirmation No.  
3634

		Copy of Office Action dated February 4, 2008 for U.S. Patent Application No. 10/861,179
		Copy of PCT International Search Report and Written Opinion for Application No. PCT/US2007/061463 dated January 23, 2008
		Copy of PCT International Search Report and Written Opinion for Application No. PCT/US2007/061481 dated March 17, 2008
		Copy of PCT International Search Report and Written Opinion for Application No. PCT/US2007/078254 dated March 28, 2008
		Sadhwani, Ajay et al., "Determination of Teflon thickness with laser speckle I. Potential for burn depth diagnosis", Optical Society of America, 1996, Vol. 35, No. 28, pages 5727-5735 φφφφφφφφ
		C.J. Stewart et al., "A comparison of two laser-based methods for determination of burn scar perfusion: Laser Doppler versus laser speckle imaging", Elsevier Ltd., 2005, Vol. 31, pages 744-752 φφφφφφφφ
		G. J. Tearney et al., "Atherosclerotic plaque characterization by spatial and temporal speckle pattern analysis", CLEO 2001, Vol. 56, pages 307-307 φφφφφφφφ
		Copy of PCT International Search Report for Application No. PCT/US2007/068233 dated February 21, 2008
		Copy of PCT International Search Report for Application No. PCT/US2007/060787 dated March 18, 2008
		Copy of Statement under Article 19 and Reply to PCT Written Opinion for PCT International Application No. PCT/US2005/043951 dated June 6, 2006
		Copy of PCT International Preliminary Report on Patentability for Application No. PCT/US2005/043951 dated June 7, 2007

4813-5455-8722\1

Examiner

Date Considered

\* Examiner: Initial citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.